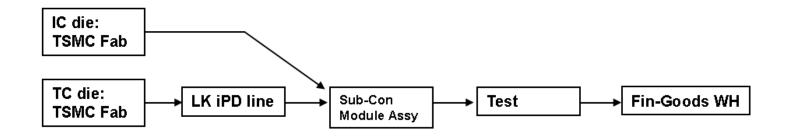
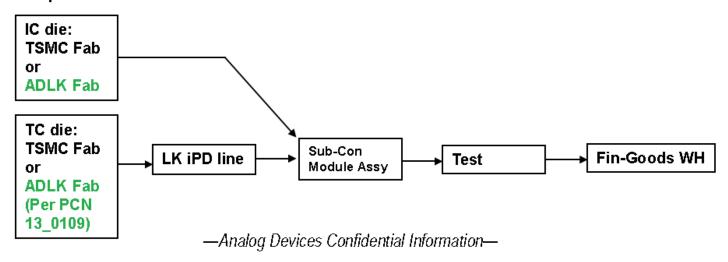
PCN 14_0173 Alternate fab source for RS-232 & RS-485 Transceiver products. To enable additional wafer fabrication capacity



Proposed Flow:



QUALIFICATION PLAN #10524			
TEST	S PECIFICATION	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC JESD22-A108	1* 77	Passed
		1* 77	Passed
Early Life Failure (ELF)	MIL-STD-883, Method 1015	3*667	Passed
High Temperature Storage Life (HTSL)	JEDEC JESD22-A103	1*45	Passed
		1*45	Passed
Latch-Up	JEDEC JESD78	6	Passed
		6	Passed
Electrostatic Discharge	ESDA/JEDEC JDS-001-	3/voltage	Passed
Human Body Model	2011	3/voltage	Passed
Electrostatic Discharge	JEDEC JESD22-C101	3/voltage	Passed
Field-Induced Charged Device Model		3/voltage	Passed
Electrostatic Discharge	~	3/voltage	Passed
Machine Model		3/voltage	Passed
Electrostatic Discharge 15kV IEC HBM	IEC 6100-4-2	3/voltage	Passed

^{*}Preconditioned per JEDEC/IPC J-STD-020